

- 3 -

Fig. 3 (a) PRIOR ART

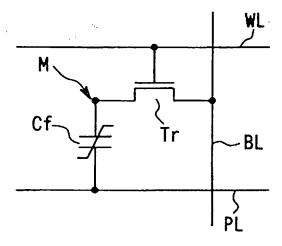
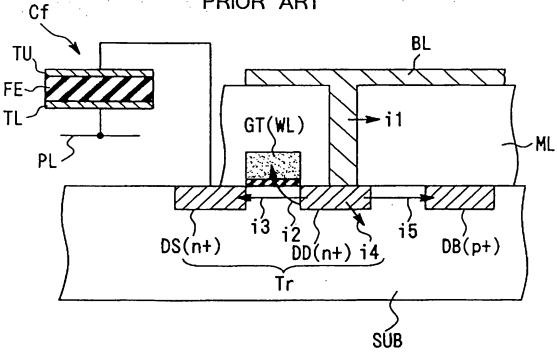
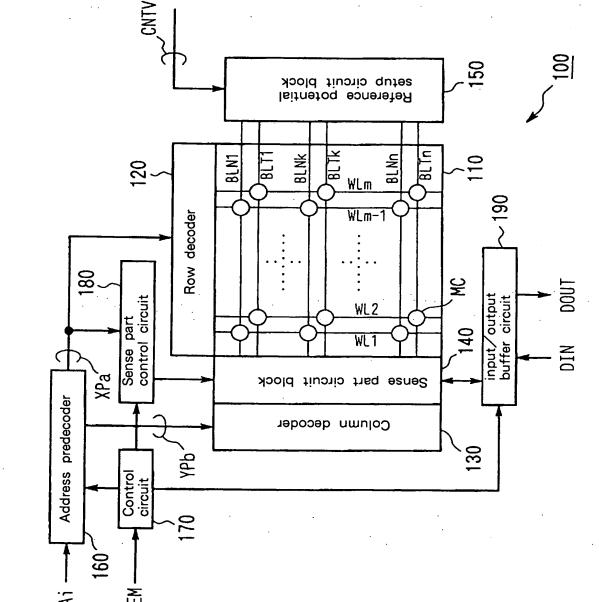


Fig. 3 (b) PRIOR ART





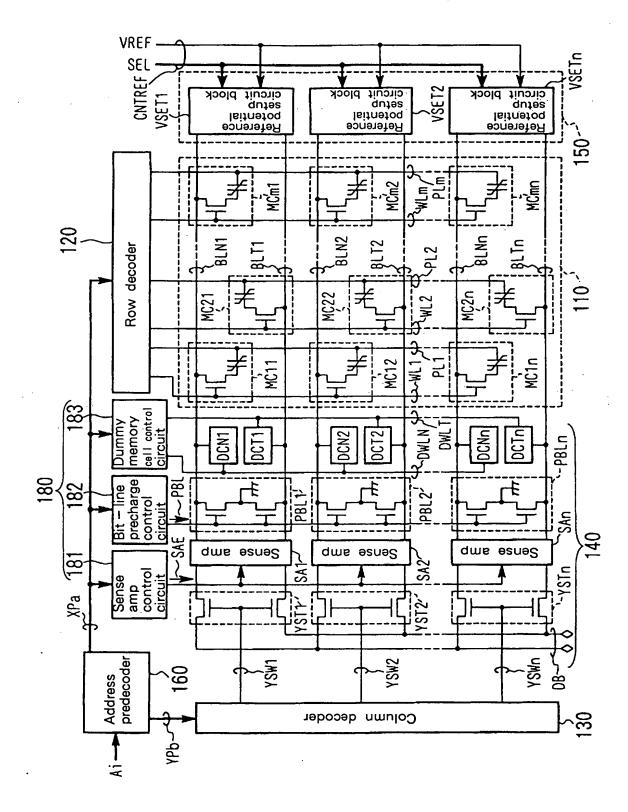
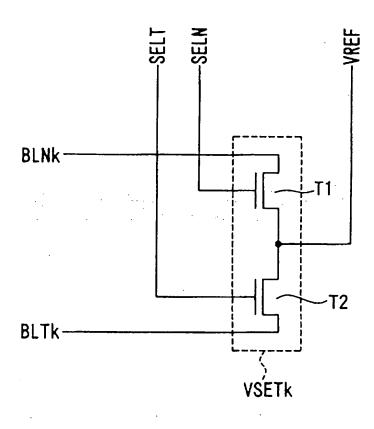


Fig. 6



rchaha razhegoa Fig. 7

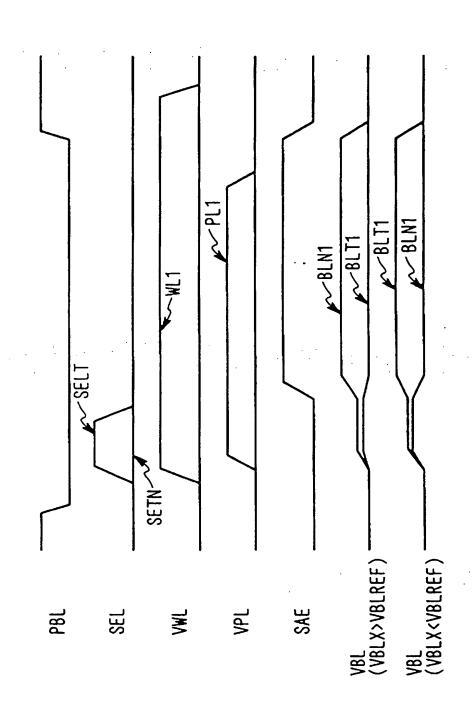
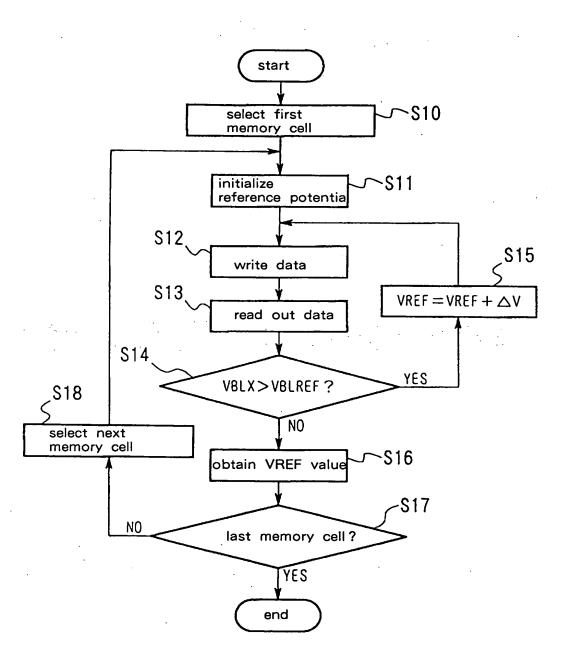
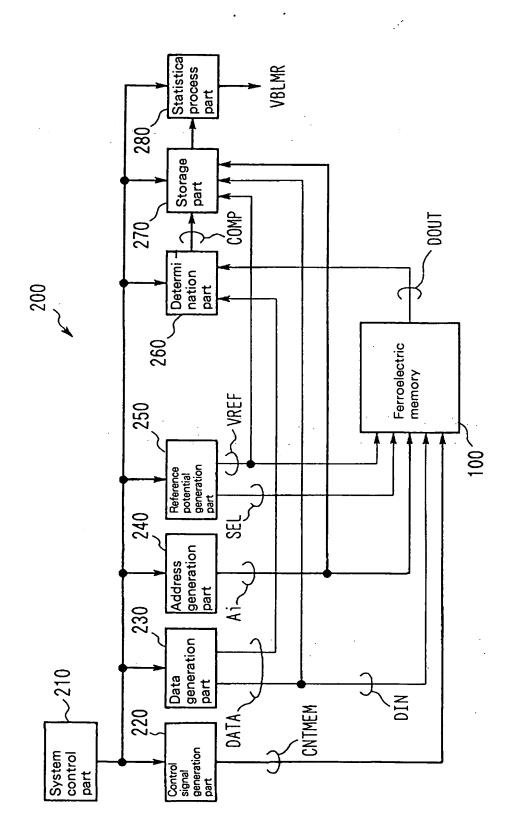


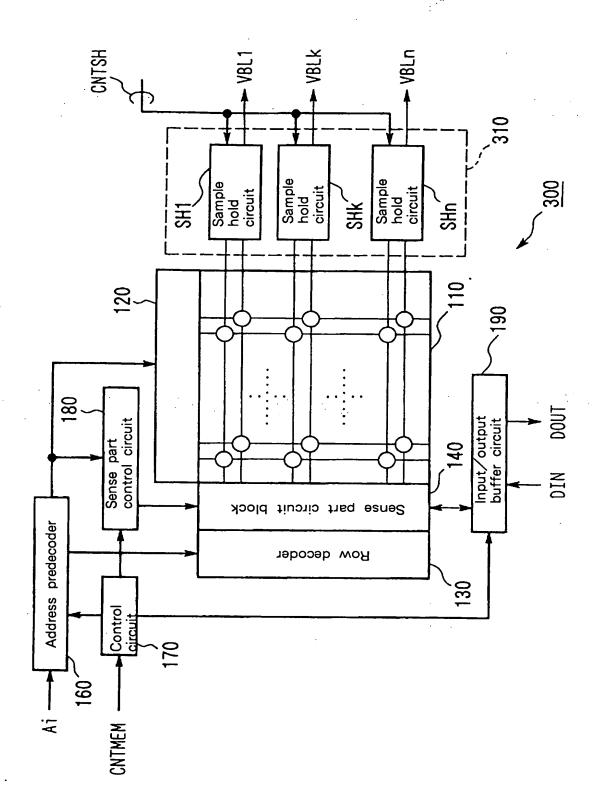
Fig. 8

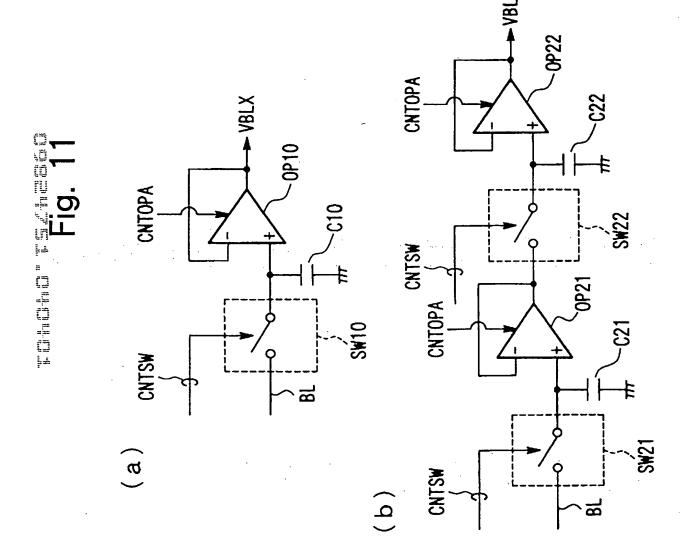






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Fig. 12

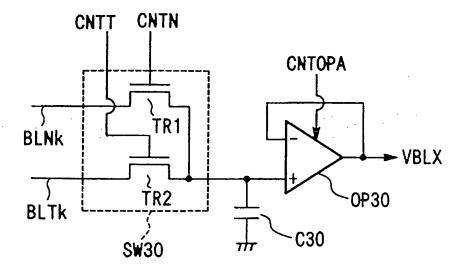
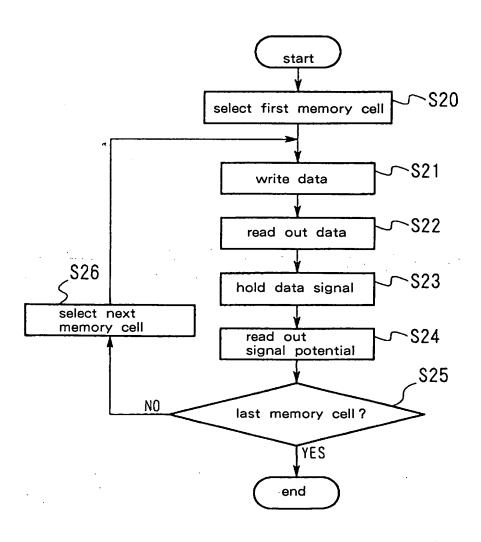
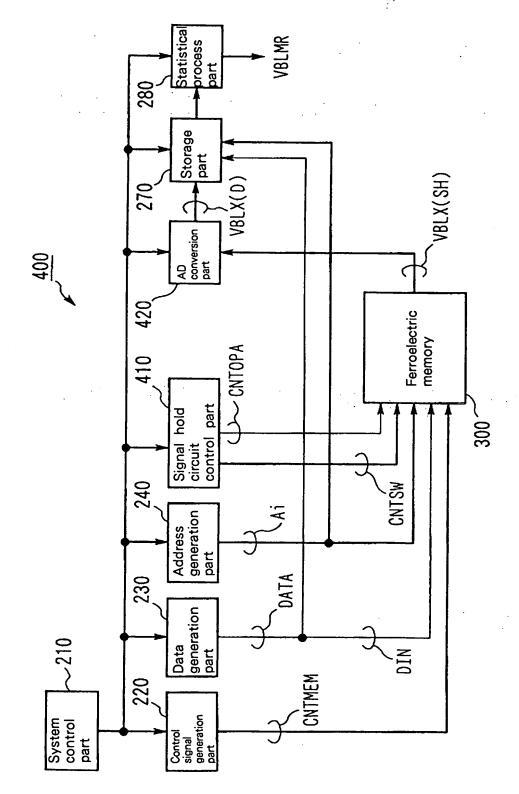


Fig. 13





rchchchrazaec Fig. 14